



Calib			oration Plan	1)	
• Steps	towards ca	libration of V	WFC3		1
- C	omponent ca	librations of f	ilters (extensive and	documented ef	fort)
– T	hermal vacu	um calibration	L N		,
– S	ervicing Miss	sion Orbital V	verification (SMOV)		
– C	ycle 17 Calił	oration			
• Syste	m Level Th	ermal Vacuu	um Testing		
– T	V#2 calibrate	es UVIS chan	nel and validates SI	overall	
- T	V#3 calibrati	on IR channe	l plus contingency		
– N	ew calibratio	ons based on A	ACS and NICMOS e	experience	
	• IR bias vs.	instrument bus	voltage		
-	Deep survey	mode UVIS a	and IR biases and da	urks	
SLTV#2	SMS's	Reviewed	Revised/Ready	Delivered	Built
UVIS	80	61	49	27	
IR	61	41	41	18	
Totals	141	102	90	45	

	NUMBER DATE FORCE TO COMPANY
	TI - TRINCOMMERA
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UVIS SLTV Procedures

Proc	Description	Proc	Description	
VE00	OS Verification	Proc	Descrip	
UV01	Darks	UV16	Detector Cutoff	
UV02	СТЕ	UV17	Filter Throughput (Narrow)	
UV03	Gain	UV19	Filter Red Leaks	
UV04	Linearity (pt src)	UV20	Filter Flats (external)	
UV05	Linearity (full frame)	UV21	Grism Flats	
UV06	Charge Injection	UV22	Fringing	
UV07	Subarray Darks/Bias	UV23	Filter Flats (internal cal sys)	
UV08	Shutter Performance	UV24	Grism Dispersion	
UV11	Encircled Energy	UV25	Ghosts	
UV12	Image Stability	UV26	Chip Gap Behavior	
UV14	Filter Throughput (Wide, Med)	UV27	Light Leaks	
UV15	System Throughput	UV28	Science Monitor	
		UV31	Electronic Crosstalk	

	IR SLTV	Pro	cedures
Proc	Description	Proc	Description
VE00	OS Verification	IR17	Ghosts & Scattered Light
IR01	Darks & Thermal Background	IR18	Light Leaks
IR02	Gain	IR19	Science Monitor
IR03	Linearity (pt src)	IR21	Readnoise vs. Gain
IR04	Linearity (full field)	IR22	Subarray Photometry
IR05	Subarray Darks	IR23	Electronic Crosstalk
IR08	Encircled Energy		
IR11	Filter Throughput		
IR12	Detector Cutoff		
IR13	Filter Flats (external)		
IR14	Grism Flats		
IR15	Filter Flats (internal cal sys)		
IR16	Grism Dispersions		

